SONY.

CX20201 A-1/-2/-3 CX20202A-1/-2/-3

10/9/8-bit 160MSPS D/A Converter

Descriptions

A series of D/A converters CX20201A/ CX20202A convert binary data into an analog signal at rates higher than 160 MHz. The devices include input data registers and have a capability of driving 75 ohms load. Three versions with linearity specifications of 10, 9 or 8 bits are available for each model.

These D/A converter ICs can be used in signal processings which require high speed and high resolution D/A conversions such as high quality displays, high definition video systems, digital measurement instruments and radars.

CX20201A-1/CX20202A-1	10-bit
CX20201A-2/CX20202A-2	9-bit
CX20201A-3/CX20202A-3	8-bit

Features

- High speed
- High accuracy
- 160 MHz
 - 10 bit (CX20201A-1/

CX20202A-1)



- Low glitch energy
- 15 pVsec 420 mW

E89667A0X-HP

- Low power consumption
- Logic invert input
 75. Ordinant duing any shill
- 75-Ω direct drive capability
 Analog multiplying function

Structure

Bipolar silicon monolithic IC.



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Block Diagram and Pin Configuration (Top View)

 Absolute Maximum F Supply voltage Digital input voltage Reference input voltage 	VEE	+0.3 to	– 7 Vee	V V	
 Analog output current 	Тоот	2	20	mA	
Operating temperature		-20 to		°C	
 Storage temperature 				°Ĉ	
 Allowable power dissipation 	PD				
CX20201A-1/-2	:/-3	87	70 п	nW	
CX20202A-1/-2	:/-3	143	30 n	nW	
Recommended Operat	ting Co	ondition	5		
 Supply voltage 			-4.75		
Digital input values		DVEE	-0.05		•
 Digital input voltage 	ViH ViL		-1.0		
 Reference input 	VREF				- 1.6
voltage	VREF		VEE + O		EE + 1.4
	_			v	cc - 1.4

Load resistanceOutput voltage RL above 75 Ω VO(FS) 8.0 to 1.2 ۷

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Pin Description

No.	Symbol	Equivalent circuit	Description
1 2 3 4 5 6 7 8 9 10	MSB D2 D3 D4 D5 D6 D7 D8 D9 LSB	DGND DGND 1-10 DVEE	Input pin for digital data. MSB and LSB are corresponded to the most significant bit and least significant bit, respectively. Pins not used should be left open or connected to DVEE.
11 12	NC		Non-connection
13 14	CLK CLK	13 13 13 13 13 13 13 13 13 13	Pins for clock inputs.
15	DVEE		Power supply pin for digital circuit.
16	INV		Code invert input pin which inverts the relation- ship between the binary code of digital data and D/A output voltage level.
17	DGND		Grounding pin for digital circuit.
18	AGND 1		Grounding pin directly connected to the R-2R output resistor circuit network in the IC. Grounding for analog circuit system.
19	NC		Non-connection

No.	Symbol	Equivalent circuit	Description
20	OUT	B AGND 1 Ro Ro AVEE	D/A analog output.
21 22 23 24 25	NC		Non-connection
26	AVEE		Power supply pin for analog circuit.
27	Vref		Bias pin which controls D/A output range. The output scale is set by the potential difference between VREF and AVEE.
28	AGND ₃		Grounding pin for analog circuit system other than the R-2R output resistor circuit network in the IC

Electrical Characteristics (1) Ta = 25°C, AVEE = DVEE = -5.2V, AGND = DGND = 0V, RL = ∞ , VO(FS) = -1V

CX20201A-1/CX20202A-1

ltem	Symbol	Min.	Тур.	Max.	Unit	
Resolution	RES		10		bit	
Differential linearity error	ELD	1/2		+1/2	LSB	
Linearity error	ELI	-0.1		+0.1	% of FS	
Settling time	ts		5.2		ns	

CX20201A-2/CX20202A-2

ltem	Symbol	Min.	Тур.	Max.	Unit
Resolution	RES		9		bit
Differential linearity error	ELD	- 1/2		+1/2	LSB
Linearity error	ELI	-0.1		+0.1	% of FS
Settling time	ts	,	4.7		ns

CX20201A-3/CX20202A-3

ltem	Symbol	Min.	Тур.	Unit	
Resolution	RES		8		bit
Differential linearity error	ELD	- 1/2		+1/2	LSB
Linearity error	ELI	-0.2		+0.2	% of FS
Settling time	ts		4.3		ns

Electrical Characteristics (2) Ta = 25°C, AVEE = DVEE = -5.2V, AGND = DGND = 0V, RL = ∞ , VO(FS) = -1V

Ite	em	Symbol	Measuring condition*1	Min.	Тур.	Max.	Unit	
Power supply	CX20201A			-60	-75 -90			
current	CX20202A	EE		-65	82	-100	mA	
Data input curre	ent	I _{TH(U)}	$V_{1H} = -0.89V$	0.1	1.5	6.0	μA	
(for upper 4 bit	s)	I _{IL(U)}	$V_{1L} = -1.75V$	0.1	1.5	6.0	μA	
Data input curre	ent	I _{IH(L)}	$V_{IH} = -0.89V$	0.1	0.75	3.0	μA	
(for lower 6 bits	s)	_{11(L)}	$V_{IL} = -1.75V$	0	0.75	3.0	μA	
Clock input curr	rent	I _{clkh}	$V_{1H} = -0.89V$	2	23	70	μA	
Invert input cur	rent	I _{INVH}	$V_{1H} = -0.89V$	0.1	1.5	6.0	μA	
Reference input	current	IREF	$V_{REF} = -4.58V$	-3	-0.4	-0.1	μA	
Output resistance	ce	R _o	lo = -1mA	52	65	78	Ω	
Maximum conve	ersion rate	fc	$R_{1} = 75\Omega$	160			MSPS	
Output voltage full-scale deviation		V _{O(FS)}	$V_{REF} = -4.58V$	0.90	1.00	1.10	v	
Set-up time		t _{su}		5.0			ns	
Hold time		t _{hd}		1.0			ns	

*1 See Figs. 3 to 5.

Data for Typical Application

Item	Symbol	Measuring condition	Тур.	Unit	
	570	$R_L \ge 10 k\Omega$	-7	- mV	
Output voltage zero offset	EZS	$R_L = 75\Omega$	- 7	עווז ך	
Output voltage full-scale		$R_L \ge 10 k\Omega$	-140	ppm/°CV	
temperature coefficient	T _{C(FS)}	$R_L = 75\Omega$	-580		
Output voltage zero offset temperature coefficient	T _{c(zs)}	$R_L \ge 10 k\Omega$	16	μV/°C	
Glitch energy	GE	Digital ramp	15	pVsec	
Rise time	t _r		1.5	ns	
Fall time	t _f	$R_L = 75\Omega$	1.5	пѕ	
Propagation delay	t _d	1	3.8	ns	
Band width for multiplying	BW _{MUL}	$R_{L} = 75\Omega,$ -3dB	14	MHz	

Timing Chart



Fig. 1

Input Coding Table

Input code	Output	Output code (V)						
	INV = 1	INV = 0						
00000	0	- 1 ;						
0 1 1 ····· 1 1 1 0 0 ····· 0 0	- 0.5	- 0.5						
111	· · ·	· · ·						

Measuring Conditions for Current Consumption, Input Current and Output Resistance (See Fig. 2.)

Test item	Symbol										wito		-											Test						
		\$1	S2	S3	S4	S5	S6	S7	S8	S9	S10	S11	S12	S13	S14	S15	S16	S17	S18	S19	S20	S21		point						
Current consumption	I _{EE}	Ъ	b	Ъ	ь	Ъ	Ъ	b	Ъ	Ъ	Ъ	Ъ	ъ	ь	b	ъ	a	Ъ	ь	Ъ	Ь	ь		I1						
_		a	ь	b	Ъ		ĺ								1				†	<u> </u>	1									
Data input current for upper	T	T	I _{IH(U)}	Ь	а	b	Ъ	Ъ	Ъ	ь	ь	Ъ	Ъ		Ъ	Ъ	Ъ	u			١.				ĺ					
4 bits (H level)	*IH(U)	ь	Ъ	a	b						U	a	U	D		Ь	Ь	Ь	Ъ	b	Ъ	Ъ		12						
		Ь	b	Ъ	a	[ļ							
Deta har a		a	b	Ъ	Ъ																									
Data input current for lower	I _{IL(U)}	ь	a	b	Ъ	Ъ	Ъ	Ъ	ь	ъ	ь	Ъ	Ъ	b	Ъ	ь	ь	ь	ь	ъ	ь	ь		12						
4 bits (L level)	-12(0)	Ъ	b	a	b							Ū	U	U	0					0			1	15						
		<u>b</u>	Ъ	Ь	a																									
								a	Ъ	b	Ь	Ъ	b					l												
Data input		.) b				b	a	b	Ь	b	Ъ									1										
current for upper 6 bits (H level)	I _{IH(L)}		ь	ь	ь	ь	ь	Ъ	a	b	Ъ	b	al	Ъ	ь	b	ь	Ъ	ь	b	b	Ь	ь		12					
						b	Ъ	b	a	Ъ	Ъ		-	-	-									12						
						b	b	b	b	a	b																			
						b	b	b	b	b	a							- • -		<u> </u>		<u> </u>	<u> </u>							
												a	b	b	Ь	b	b													
Data input																	b	a	b	b	<u>ь</u>	b	_							
current for lower	$I_{IL(L)}$	ь	b	Ъ	ь	b	b	a L	Ъ	b	b	ь	Ь	b	b	ь	ъ	ь	b	Ъ	Ъ	ь		I 2						
6 bits (L level)						b b	b	b b	a	Ь	b																			
						b b	b b	D b	b b	a b	b								i											
Clock input			•				-	0	0		a												—							
current (H level)	I _{CLKH}	Ъ	Ь	b	ь	Ъ	Ъ	ь	Ъ	Ъ	b	Ь	а	Ъ	Ъ	a	Ъ	Ъ	ь	Ъ	Ъ	Ъ		Ι3						
Clock-bar input current (H level)	ICLEH	b	b	b	b	b	Ъ	Ь	b	Ъ	ь	ь	ь	a	a	ь	ь	b	Ъ	Ъ	ь	Ъ		I 4						
Invert input current (H level)	I _{invh}	b	ь	b	b	ь	Ъ	b	b	ь	ь	b	ь	ь	b	Ъ	ь	a	a	b	b	b		I 5						
Referecnce input current	Iref	ò	b	Ъ	ь	b	ь	ь	ь	b	b	ь	ь	Ъ	ь	b	Ъ	b	b	ь	b	a		I 6						
Output resistance	Ro	Ъ	b	ь	b	Ь	ь	Ъ	ь	Ъ	Ъ	ь	ъ	Ъ	ь	ь	Ъ	b	Ъ	a	a	ь		V1						

Electrical Characteristics Test Circuit

Test Circuit for Current Consumption, Input Current and Output Resistance



Test Circuit for Differential Linearity Error and Linearity Error



Linearit	у егг	ors a	are meas	ured	as folio	ws.
· S1	S2	S3	•••••	S9	S10	D∕A out
0	0	0		0	0	Vo
0	0	0		0	1	V ₁
0	0	0		1	0	V ₂
1	1	1	;	1	1	:
T	1	T		T	1	V1023

Linearity error Differential linearity error

Vo	
V ₁	$V_1 = V_0$
V ₂	V_2-V_1
V4	$V_4 - V_3$
V ₆	$V_8 - V_7$
V ₁₆	$V_{16} - V_{15}$
V3 2	$V_{3 2} - V_{3 1}$
V _{6 4}	V6 4 - V6 3
V128	$V_{128}-V_{127}$
V1.92	$V_{192} = V_{191}$
: V960	: V960 — V959
V1023	*¥0V *959

Adjust so that the full scale of DC voltage at Pin 20 becomes 1.023V, that is, to satisfy V0 - V1023 = 1.023V. Fig. 3

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Errors at individual measurement points are calculated according to the following definition. $(V_{1023} - V_0)/1023 = V_0(FS)/1023 \equiv 1 LSB.$



Test Circuit for Multiplying Band Width



Notes on Applications

(1) Setting of full-scale output voltage

The full-scale output voltage (VO(FS)) is set by the pin 27 (VREF). VO(FS) varies in proportion to the voltage difference between pin 27 and pin 26 (AVEE) as shown in Fig. 9.

VO(FS) can be set by simply dividing the supply voltage using resistors as shown in Fig. 8, but in this simple set up the voltage deviation of the supply voltage result in a deviation of VO(FS). This influence can be avoided by using a stabilization circuit as shown in Fig. 7 to allow stable full-scale output.

Pin 27 (VREF) should be stabilized against high-frequency noise by sufficient by passing using a capacitor with low lead inductance such as ceramic chip capacitors. The stabilization capacitor should be inserted between pin 27 (VREF) and pin 26 (AVEE) as VO(FS) is direct proportion to the voltage across these two terminals.



(2) Noise reduction

An external digital noise should be minimized because the system handles small analog voltage (1 LSB corresponds 1 mV of analog output voltage for 10 bit resolution). Refer to the following notes to minimize the system noise contamination.

- Ground plane and VEE plane on a printed circuit board should be made as wide as possible to reduce parasitic inductance and resistance.
- The patterns AGND and DGND should be separated on the printed circuit board. AVEE and DVEE should be separated too. The connections between analog system and digital system are to be made at the I/O ports of the printed circuit board.
- AVEE and DVEE should be bypassed to respective GND by using a tantalum capacitor of 1 μ F and a ceramic chip capacitor of 47 μ F positioned as close as to terminals of the IC.
- Pins not in sure are to be connected to the ground plane.

(3) Load resistance and temperature coefficient

Temperature coefficient of the full-scale output voltage and zero offset voltage depend on the load resistance (value and type). Generally, the larger the load resistance the better the temperature coefficient value. Temperature characteristics at $RL \ge 10 \text{ k}\Omega$ and $RL = 75 \Omega$ are shown in Fig. 10.

(4) Input data and internal latching circuit

CX20201A/CX20202A incorporates a latching circuit as shown in the block diagram. This latching circuit has a two-stage configuration (master-slave type) and fetches input data only at the rising edge of the clock; the output is not affected by the changes in input data at any other timings. This mechanism allows stable operation against any changes in input data at any timings, except for the set-up time immediately before and the hold time immediately after the clock change from L to H.

(5) Driving input data and clock

CX20201A/CX20202A are designed to be operated at very high speed. It is, therefore, necessary to drive it with a high-speed ICs such as an ECL100K for full performance. Also the output port of the data and clock drivers should be terminated with 50- Ω systems. See Figs. 4 and 7.



Package Outline Unit : mm



28pin SOP(Plastic) 375mil 0.6g



CX20202A

28pin DIP(Plastic) 600mil 4.2g

